

PATENT APPLICATION

IN THE UNITED STATES PATENT AND TRADEMARK OFFICE

In re the Application of

Hiroaki TAKAIWA et al.

New U.S. National Phase of PCT/JP2005/001225

Filed: July 26, 2006

Docket No.: 128865

For: EXPOSURE APPARATUS AND DEVICE MANUFACTURING METHOD

INFORMATION DISCLOSURE STATEMENT

Commissioner for Patents
P.O. Box 1450
Alexandria, VA 22313-1450

Sir:

Pursuant to 37 CFR §1.56, the attention of the Patent and Trademark Office is hereby directed to the references listed on the attached PTO-1449. Unless otherwise indicated herein, one copy of each reference is attached. It is respectfully requested that the information be expressly considered during the prosecution of this application, and that the references be made of record therein and appear among the "References Cited" on any patent to issue therefrom.

- ☒ 1. This Information Disclosure Statement is being filed (a) within three months of the U.S. filing date of this non-CPA application, OR (b) before the mailing date of a first Office Action on the merits in the present application. No certification or fee is required.
- ☒ 2. Relevance of one or more non-English language reference is discussed in the present specification. See Reference 48.
- ☒ 3. One or more reference cited herein was cited in the International Search Report. An English language version of the International Search Report is attached for the Examiner's information. See References 19, 21, 22 and 24-26.
- ☒ 4. In accordance with 37 CFR §1.98(a)(2)(ii), copies of any U.S. patents and patent application publications are not attached.
- ☒ 5. An English language Abstract of one or more non-English language reference is attached hereto. See References 19-48, 50 and 52-59.
- ☒ 6. A computer-generated English language translation of one or more Japanese Patent Publication cited herein has been obtained from the website of the Japanese Patent Office ([<http://www.jpo.go.jp>]), and is attached, but has not been reviewed for accuracy. See References 19, 21, 22, 24, 25, 28, 30, 31, 33-35, 37, 39-41, 44-48 and 56-59.

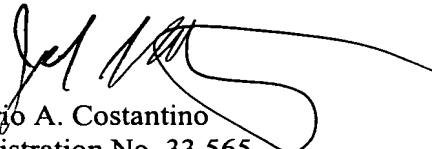
10/587268

New U.S. National Phase of PCT/JP2005/001225

IAP11 Rec'd PCT/PTO 26 JUL 2006

- ☒ 7. Reference 1 corresponds to reference 21. Reference 2 corresponds to reference 24. Reference 16 corresponds to reference 25. Reference 20 corresponds to reference 19. Reference 23 corresponds to reference 22.

Respectfully submitted,


Mario A. Costantino
Registration No. 33,565

Joel S. Armstrong
Registration No. 36,430

MAC:JSA/jdb

Date: July 26, 2006

OLIFF & BERRIDGE, PLC
P.O. Box 19928
Alexandria, Virginia 22320
Telephone: (703) 836-6400

<p>DEPOSIT ACCOUNT USE AUTHORIZATION Please grant any extension necessary for entry; Charge any fee due to our Deposit Account No. 15-0461</p>
--

Form PTO-1449 (REV. 1/06)		US Dept. of Commerce PATENT & TRADEMARK OFFICE		ATTY DOCKET NO. 128865		APPLICATION NO. New U.S. National Phase of PCT/JP2005/001225	
INFORMATION DISCLOSURE STATEMENT (Use several sheets if necessary)				APPLICANTS Hiroaki TAKAIWA et al.			
				FILING DATE July 26, 2006			

U.S. PATENT DOCUMENTS				
Examiner Initials	Cite No.	Document Number	Date	Name
	1	2005/0048220 A1	03/03/2005	Mertens et al.
	2	2005/0024609 A1	02/03/2005	De Smit et al.
	3	6,341,007 B1	01/22/2002	Nishi et al.
	4	5,969,441	10/19/1999	Loopstra et al.
	5	5,528,118	06/18/1996	Lee
	6	6,400,441 B1	06/04/2002	Nishi et al.
	7	5,874,820	02/23/1999	Lee
	8	5,825,043	10/20/1998	Suwa
	9	6,549,269 B1	04/15/2003	Nishi et al.
	10	6,590,634 B1	07/08/2003	Nishi et al.
	11	6,208,407 B1	03/27/2001	Loopstra
	12	5,623,853	04/29/1997	Novak et al.
	13	2004/0020782 A1	02/05/2004	Cohen et al.
	14	4,346,164	08/24/1982	Tabarelli et al.
	15	4,480,910	11/06/1984	Takanashi et al.
	16	5,610,683	03/11/1997	Takahashi
	17	5,715,039	02/03/1998	Fukuda et al.
	18	2004/0165159 A1	08/26/2004	Lof et al.

FOREIGN PATENT DOCUMENTS						
Examiner Initials	Cite No.	Document Number	Date	Country	With English Abstract	With English Translation
	19	JP A 2004-207696	07/22/2004	Japan	X	X
	20	WO 2004/053958 A1	06/24/2004	WIPO	X	

OTHER DOCUMENTS		
Examiner Initials	Cite No.	(Including Author, Title, Date, Pertinent Pages, etc.)

EXAMINER	DATE CONSIDERED
----------	-----------------

Examiner:	Initial if citation considered, whether or not citation is in conformance with M.P.E.P. 609; draw line through citation if not in conformance and not considered. Include copy of this form with next communication to applicant.
-----------	---

Date: July 26, 2006

11 Dec 2006 PCT/PTO 26 JUL 2006

10/587268

Sheet 2 of 4

Form PTO-1449 (REV. 1/06)		US Dept. of Commerce PATENT & TRADEMARK OFFICE		ATTY DOCKET NO. 128865		APPLICATION NO. New U.S. National Phase of PCT/JP2005/001225	
INFORMATION DISCLOSURE STATEMENT (Use several sheets if necessary)				APPLICANTS Hiroaki TAKAIWA et al.			
				FILING DATE July 26, 2006			

U.S. PATENT DOCUMENTS				
Examiner Initials	Cite No.	Document Number	Date	Name

FOREIGN PATENT DOCUMENTS						
Examiner Initials	Cite No.	Document Number	Date	Country	With English Abstract	With English Translation
	21	JP A 2005-57278	03/03/2005	Japan	X	X
	22	JP A 2005-12195	01/13/2005	Japan	X	X
	23	WO 2004/105106 A1	12/02/2004	WIPO	X	
	24	JP A 2005-5713	01/06/2005	Japan	X	X
	25	JP A 6-168866	06/14/1994	Japan	X	X
	26	JP A 63-73628	04/04/1988	Japan	X	
	27	WO 2005-076321 A1	08/18/2005	WIPO	X	
	28	JP A 6-188169	07/08/1994	Japan	X	X
	29	JP A 11-135400	05/21/1999	Japan	X	
	30	JP A 10-163099	06/19/1998	Japan	X	X
	31	JP A 10-214783	08/11/1998	Japan	X	X
	32	WO 98/28665	07/02/1998	WIPO	X	
	33	JP A 8-166475	06/25/1996	Japan	X	X
	34	JP A 8-330224	12/13/1996	Japan	X	X
	35	JP A 8-37149	02/06/1996	Japan	X	X
	36	JP A 4-65603	03/02/1992	Japan	X	
	37	JP A 7-176468	07/14/1995	Japan	X	X

OTHER DOCUMENTS	
Examiner Initials	Cite No. (Including Author, Title, Date, Pertinent Pages, etc.)

EXAMINER	DATE CONSIDERED
----------	-----------------

Examiner: Initial if citation considered, whether or not citation is in conformance with M.P.E.P. 609; draw line through citation if not in conformance and not considered. Include copy of this form with next communication to applicant.

Date: July 26, 2006

LAP11 Rec'd PCT/PTO 26 JUL 2006

10/587268

Sheet 3 of 4

Form PTO-1449 (REV. 1/06)		US Dept. of Commerce PATENT & TRADEMARK OFFICE		ATTY DOCKET NO. 128865		APPLICATION NO. New U.S. National Phase of PCT/JP2005/001225	
INFORMATION DISCLOSURE STATEMENT (Use several sheets if necessary)				APPLICANTS Hiroaki TAKAIWA et al.			
				FILING DATE July 26, 2006			
U.S. PATENT DOCUMENTS							
Examiner Initials	Cite No.	Document Number	Date	Name			
FOREIGN PATENT DOCUMENTS							
Examiner Initials	Cite No.	Document Number	Date	Country	With English Abstract	With English Translation	
	38	JP A 57-117238	07/21/1982	Japan	X		
	39	JP A 2002-14005	01/18/2002	Japan	X	X	
	40	JP A 11-16816	01/22/1999	Japan	X	X	
	41	JP A 6-53120	02/25/1994	Japan	X	X	
	42	JP A 4-305915	10/28/1992	Japan	X		
	43	JP A 4-305917	10/28/1992	Japan	X		
	44	JP A 10-303114	11/13/1998	Japan	X	X	
	45	JP A 10-340846	12/22/1998	Japan	X	X	
	46	JP A 11-176727	07/02/1999	Japan	X	X	
	47	JP A 2000-58436	02/25/2000	Japan	X	X	
	48	WO 99/49504	09/30/1999	WIPO	X	X	
	49	WO 2004/019128 A2	03/04/2004	WIPO			
	50	DD 221 561 A1	04/24/1985	Germany	X	X	
	51	DD 224 448 A1	07/03/1985	Germany		X	
	52	JP A 63-157419	06/30/1988	Japan	X		
	53	JP A 58-202448	11/25/1983	Japan	X		
	54	JP A 59-19912	02/01/1984	Japan	X		
	55	JP A 62-65326	03/24/1987	Japan	X		
OTHER DOCUMENTS							
Examiner Initials	Cite No.	(Including Author, Title, Date, Pertinent Pages, etc.)					
EXAMINER					DATE CONSIDERED		
Examiner: Initial if citation considered, whether or not citation is in conformance with M.P.E.P. 609; draw line through citation if not in conformance and not considered. Include copy of this form with next communication to applicant.							

Date: July 26, 2006

10/587268 Sheet 4 of 4

Form PTO-1449 (REV. 1/06)		US Dept. of Commerce PATENT & TRADEMARK OFFICE		ATTY DOCKET NO. 128865		APPLICATION NO. New U.S. National Phase of PCT/JP2005/001225	
INFORMATION DISCLOSURE STATEMENT (Use several sheets if necessary)				APPLICANTS Hiroaki TAKAIWA et al.			
				FILING DATE July 26, 2006			
U.S. PATENT DOCUMENTS							
Examiner Initials	Cite No.	Document Number	Date	Name			
FOREIGN PATENT DOCUMENTS							
Examiner Initials	Cite No.	Document Number	Date	Country	With English Abstract	With English Translation	
	56	JP A 5-62877	03/12/1993	Japan	X	X	
	57	JP A 6-124873	05/06/1994	Japan	X	X	
	58	JP A 7-220990	08/18/1995	Japan	X	X	
	59	JP A 8-316125	11/29/1996	Japan	X	X	
OTHER DOCUMENTS							
Examiner Initials	Cite No.	(Including Author, Title, Date, Pertinent Pages, etc.)					
EXAMINER					DATE CONSIDERED		
Examiner: Initial if citation considered, whether or not citation is in conformance with M.P.E.P. 609; draw line through citation if not in conformance and not considered. Include copy of this form with next communication to applicant.							

Date: July 26, 2006